

Abstract Submitted  
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**Exciton binding energy and electron effective-mass in strain compensated InGaAsN/GaAs single Quantum Well**<sup>1</sup> LIFANG XU, DINESH PATEL, CARMEN MENONI, Department of Electrical and Computer Engineering, Colorado State University, Fort Collins, CO 80523-1373, JENGYA YEH, LUKE MAWST, Reed Center for Photonics, Department of Electrical & Computer Engineering, University of Wisconsin-Madison, Madison, WI 53706, NELSON TANSU, Center for Optical Technologies, Department of Electrical and Computer Engineering, Lehigh University, Sinclair Laboratory, 7 Asa Drive, Bethlehem, PA — A detailed lineshape analysis of the temperature dependent photoluminescence spectra of  $\text{In}_{0.4}\text{Ga}_{0.6}\text{As}_{1-y}\text{N}_y/\text{GaAs}$  quantum well (QW) ( $y=0; 0.005$ ) is carried out. The analysis extracts the binding energy of the  $e_1\text{-hh}_1$  ground-state exciton which equals  $9.72\pm 1.24$  meV and  $17.5\pm 0.9$  meV for InGaAs and InGaAsN ( $N=0.5\%$ ) single QW sample, respectively. By using a fractional dimension exciton binding energy model, an electron effective mass of  $m_e^*=(0.11\pm 0.015)m_0$  is determined for the highly strained dilute nitride single QW.

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Lifang Xu

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